

## Claims

1. (currently amended) A thin film layer structure for use in magnetic recording comprising:

a pre-seed layer of CrTiAl having an amorphous or nanocrystalline structure;

at least one seed layer above the pre-seed layer;

at least one underlayer above the seed layer; and

at least one magnetic layer above the underlayer.

2. (currently amended) The thin film structure of claim 1 wherein the further comprising a seed layer of is RuAl above the layer of CrTiAl, the RuAl having a B2 crystallographic structure.

3. (currently amended) The thin film layer structure of claim 1 wherein the pre-seed layer of CrTiAl is approximately 5 to 20 at % aluminum.

4. (currently amended) The thin film layer structure of claim 1 wherein the pre-seed layer of CrTiAl is deposited on a circumferential textured nonmetallic substrate.

5. (currently amended) A magnetic thin film storage medium comprising:

a substrate;

a layer of CrTiAl deposited on the substrate, the CrTiAl having an amorphous or nanocrystalline structure;

a layer of RuAl over the layer of CrTiAl; and

at least one underlayer over the layer of RuAl

at least one magnetic layer over the underlayer.

6. (original) The magnetic thin film storage medium of claim 5 wherein the CrTiAl has from 5 to 20 at % aluminum.

7. (original) The magnetic thin film storage medium of claim 5 wherein the CrTiAl has approximately from 5 to 20 at.% aluminum with the remainder being approximately equal atomic percentages of chromium and titanium.
8. (original) The magnetic thin film storage medium of claim 5 wherein the RuAl has a B2 crystallographic structure.
9. (original) The magnetic thin film storage medium of claim 5 wherein the CrTiAl is approximately from 10 to 30 nm thick.
10. (currently amended) A method of fabricating a magnetic thin film storage medium comprising the steps of:
  - depositing a layer of CrTiAl on a substrate, the CrTiAl having an amorphous or nanocrystalline structure;
  - depositing a layer of RuAl over the layer of CrTiAl; and
  - depositing a plurality of layers over the layer of RuAl, including at least one magnetic layer.
11. (original) The method of claim 10 wherein the CrTiAl has from 5 to 20 at.% aluminum.
12. (original) The method of claim 10 wherein the CrTiAl has approximately from 5 to 20 at.% aluminum with the remainder being approximately equal atomic percentages of chromium and titanium.
13. (original) The method of claim 10 wherein the RuAl has a B2 crystallographic structure.
14. (original) The method of claim 10 wherein the CrTiAl is from approximately from 10 to 30 nm thick.

15. (currently amended) A disk drive comprising:  
a magnetic transducer including a read and a write head;  
a spindle; and  
a magnetic thin film disk mounted on the spindle, the magnetic thin film disk including a layer of CrTiAl followed by a layer of RuAl and at least one magnetic layer, the CrTiAl having an amorphous or nanocrystalline structure.
16. (original) The disk drive of claim 15 wherein the CrTiAl has from 5 to 20 at % aluminum.
17. (original) The disk drive of claim 15 wherein the CrTiAl has approximately from 5 to 20 at % aluminum with the remainder being approximately equal atomic percentages of chromium and titanium.
18. (original) The disk drive of claim 15 wherein the RuAl has a B2 crystallographic structure.
19. (original) The disk drive of claim 15 wherein the CrTiAl is approximately from 10 to 30 nm thick.